

In re Appln. of Humphris et al.
Application No. Unassigned
(U.S. National Phase of PCT/GB2004/003065)

Amendments to the Abstract

Please replace the Abstract with the following replacement Abstract:

A probe (22) for an atomic force microscope is adapted such that, as a sample (14) is scanned, it experiences a biasing force F_{direct} urging the probe towards the sample. This improves probe tracking of the sample surface and faster scans are possible. This is achieved by either including a biasing element (24, 50), which is responsive to an externally applied force, on the probe (22) and / or reducing the quality factor of a supporting beam. This biasing element may, for example, be a magnet (24) or an electrically-conducting element (50). The quality factor may be reduced by coating the beam with a mechanical-energy dissipating material.

A replacement Abstract is attached hereto on a separate sheet in accordance with 37 CFR 1.72